

_	Application/Control No.	Applicant(s)/Patent Reexamination	under
	10/665,056	JIN ET AL.	
	Examiner	Art Unit	
	Anu M. Mofiz	2165	

	SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Inventor Sent	0408/07	An		
EZUT - USPAPUS - USPAPUS - USPAPUS - IBM TOB - DERWONT				
NPL -ACM - IEEE				
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